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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>		Application Number	Unassigned <i>10/15/2022</i>
		Filing Date	October 19, 2004
		First Named Inventor	Tetsuhiro et al.
		Art Unit	<del>Unassigned</del> <i>1723</i>
		Examiner Name	<del>Unassigned</del> <i>Hiteshew</i>
Sheet	1	of	1
		Attorney Docket Number	
		93120	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>8</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	MM-DD-YYYY			
F.H.		JP 63123893	05/27/1988	Shoichi et al.		Abstract
F.H.		JP 03080184	04/04/1991	NEC Corporation		Abstract
F.H.		JP 57-017494	01/29/1982	Toshiba Corporation		Abstract
F.H.		JP 09-165298	06/24/1997	Koji et al.		Abstract

NON PATENT LITERATURE DOCUMENTS		
Examiner Initials'	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
FIT		Murthy et al.; "Growth of Dislocation-Free Silicon Crystals in the (110) Direction for Use as Neutron Monochromators," <i>Journal of Crystal Growth</i> , Vol. 52, (1981), pp. 391-395.
FII		Hoshikawa et al.; "Dislocation-Free Czochralski Silicon Crystal Growth without the Dislocation-Elimination-Necking Process," <i>Japan Journal of Applied Phys.</i> , Vol. 38 (1999) pp. L1369-L1371.

Examiner Signature		Date Considered	8/8/04
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